



FQD7N10 / FQU7N10

100V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

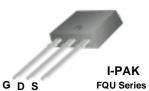
This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as audio amplifiers, high efficiency switching DC/DC converters, and DC motor control.

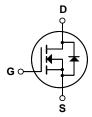
Features

- 5.8A, 100V, $R_{DS(on)}$ = 0.35 Ω @V_{GS} = 10 V Low gate charge (typical 5.8 nC)
- Low Crss (typical 10 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD7N10 / FQU7N10	Units
V _{DSS}	Drain-Source Voltage		100	V
I _D	Drain Current - Continuous (T _C = 25°C	()	5.8	А
	- Continuous (T _C = 100°C)		3.67	А
I _{DM}	Drain Current - Pulsed	(Note 1)	23.2	А
V _{GSS}	Gate-Source Voltage		± 25	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	50	mJ
I _{AR}	Avalanche Current	(Note 1)	5.8	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns
P _D	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C) - Derate above 25°C		25	W
			0.2	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		5.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Condition	s	Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C			0.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 100 V, V _{GS} = 0 V				1	μΑ
		V _{DS} = 80 V, T _C = 125°C				10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 25 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$		1		-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 2.9 A			0.28	0.35	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_{D} = 2.9 \text{ A}$	(Note 4)		3.3		S
C _{iss} C _{oss}	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			190	250 75	pF pF
	' '				10	13	-
C _{rss}	Reverse Transfer Capacitance				10	13	pF
Switchi	ng Characteristics						
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 50 \text{ V}, I_{D} = 7.3 \text{ A},$ $R_{G} = 25 \Omega$		7	25	ns	
t _r	Turn-On Rise Time			24	60	ns	
t _{d(off)}	Turn-Off Delay Time	(Note 4, 5)			13	35	ns
t _f	Turn-Off Fall Time				19	50	ns
Qg	Total Gate Charge	$V_{DS} = 80 \text{ V}, I_{D} = 7.3 \text{ A},$			5.8	7.5	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V (Note 4, 5)			1.4		nC
Q _{gd}	Gate-Drain Charge				2.5		nC
Drain-S	ource Diode Characteristics ar	nd Maximum Rating	ıs				
I _S	Maximum Continuous Drain-Source Diode Forward Current				5.8	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode F	Diode Forward Current				23.2	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 5.8 \text{ A}$				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 7.3 \text{ A,}$ $dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			70		ns
Q _{rr}	Reverse Recovery Charge				150		nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.23mH, $I_{AS} = 5.8A$, $V_{DD} = 25V$, $R_G = 25~\Omega$, Starting $T_J = 25^\circ C$ 3. $I_{SD} \le 7.3A$, di/dt $\le 300 \text{A}/\mu \text{s}$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^\circ C$ 4. Pulse Test : Pulse width $\le 300\mu \text{s}$, Duty cycles 2% 5. Essentially independent of operating temperature

Typical Characteristics

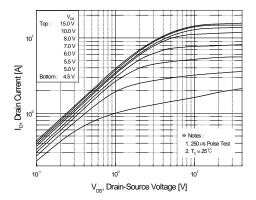


Figure 1. On-Region Characteristics

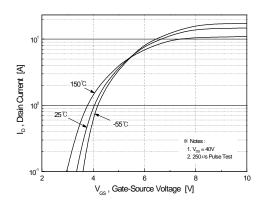


Figure 2. Transfer Characteristics

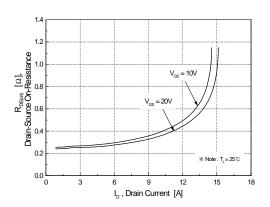


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

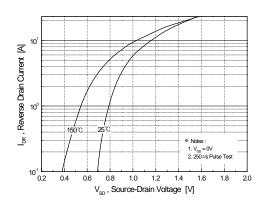


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

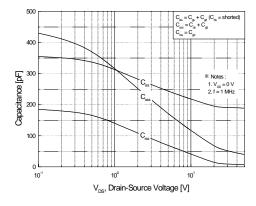


Figure 5. Capacitance Characteristics

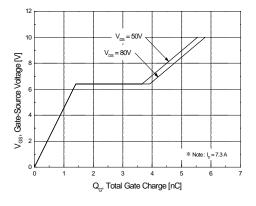
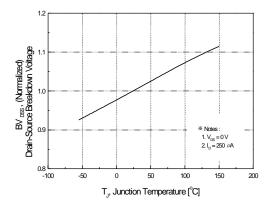


Figure 6. Gate Charge Characteristics

©2008 Fairchild Semiconductor International Rev. A3, October 2008

Typical Characteristics (Continued)



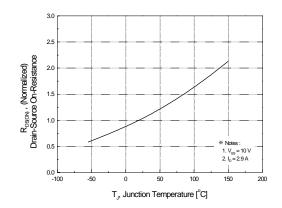
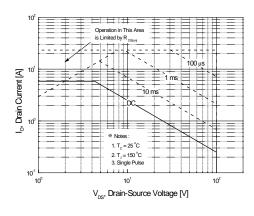


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



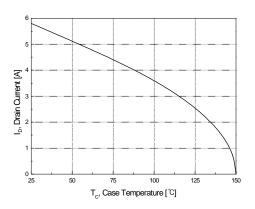


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

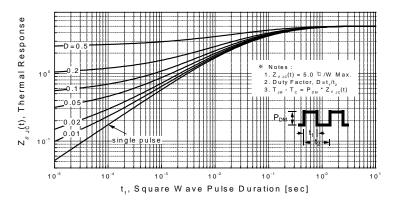
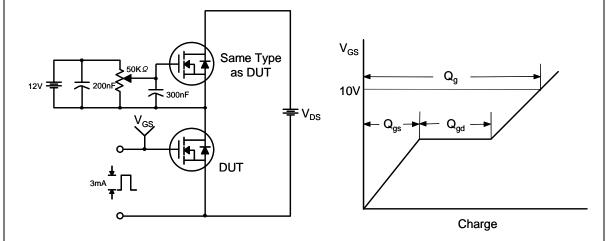


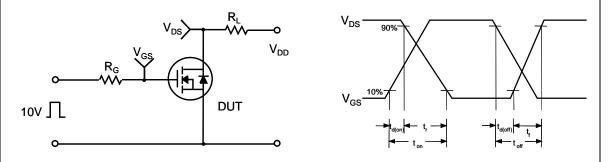
Figure 11. Transient Thermal Response Curve

©2008 Fairchild Semiconductor International Rev. A3, October 2008

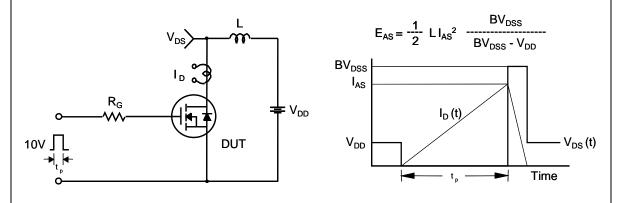
Gate Charge Test Circuit & Waveform



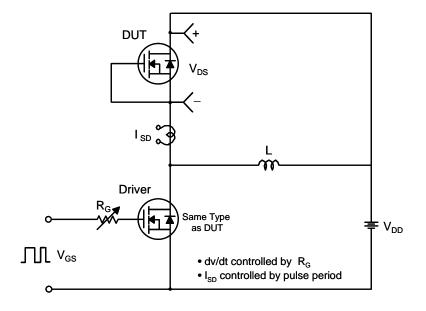
Resistive Switching Test Circuit & Waveforms

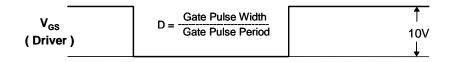


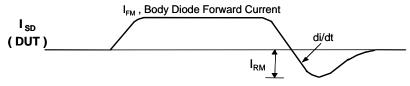
Unclamped Inductive Switching Test Circuit & Waveforms



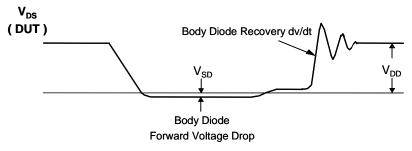
Peak Diode Recovery dv/dt Test Circuit & Waveforms





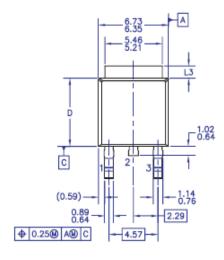


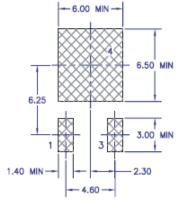
Body Diode Reverse Current



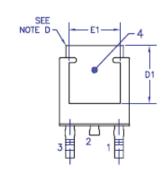
Mechanical Dimensions

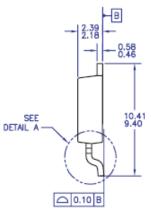
D - PAK

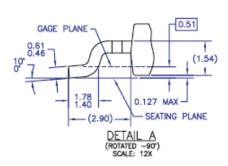








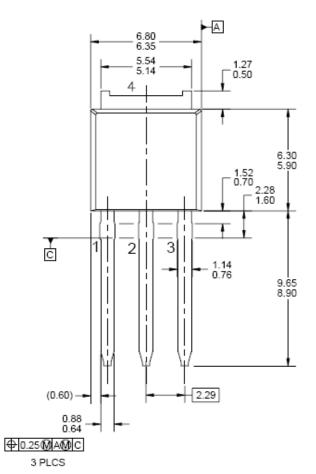


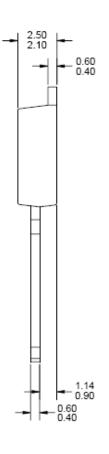


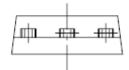
Dimensions in Millimeters

Mechanical Dimensions

I - PAK







Dimensions in Millimeters





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

Build it Now™ CorePLUS™ CorePOWER™ $CROSSVOLT^{\text{TM}}$ CTI ™ Current Transfer Logic™

FcoSPARK® EfficentMax™ EZSWITCH™ *

Fairchild®

Fairchild Semiconductor® FACT Quiet Series™

FACT® FAST® FastvCore™ FlashWriter® * FPS™ F-PFS™

FRFET® Global Power ResourceSM Green FPS™ Green FPS™ e-Series™ GTO™

IntelliMAX™ ISOPI ANAR™ MegaBuck™ MICROCOUPLER™ MicroFET™

MicroPak™ MillerDrive™ MotionMax™ Motion-SPM™ OPTOLOGIC® OPTOPLANAR®

PDP SPM™ Power-SPM™ PowerTrench® PowerXS™

Programmable Active Droop™ QFET QSTM Quiet Series™

RapidConfigure™

Saving our world, 1mW /W /kW at a time™ SmartMax™ SMART START™ SPM® STEALTH™

SuperFET™ SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS™ SyncFET™

SYSTEM ® GENERAL The Power Franchise® prewer TinyBoost™ TinyBuck™ TinyLogic[®] TIŃYOPTO™ TinyPower™ TinyPWM™ TinyWire™ μSerDes™

从 SerDes" UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ XS™

* EZSWITCH™ and FlashWriter® are trademarks of System General Corporation, used under license by Fairchild Semiconductor

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

EIPE SUPPORT FOLICE.

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Farichild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Farichild strongly encourages customers to purchase Farichild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Farichild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I37

FQD7N10 / FQU7N10 Rev. A3 www.fairchildsemi.com